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APPLICATION NO.		FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/812,035		03/30/2004	Linda T. Romano	108905.01	108905.01 1425 EXAMINER	
27074	7590	04/12/2006		EXAM		
OLIFF & E		GE, PLC.	LOUIE, W	LOUIE, WAI SING		
P.O. BOX 19928 ALEXANDRIA, VA 22320		22320		ART UNIT	PAPER NUMBER	
	,			2814		
				DATE MAILED: 04/12/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

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		Application No.	Applicant(s)	
•		10/812,035	ROMANO ET AL.	
	Office Action Summary	Examiner	Art Unit	
		Wai-Sing Louie	2814	
Period fo	The MAILING DATE of this communication app or Reply	pears on the cover sheet with the c	orrespondence address	
WHIC - Exter after - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING Donsions of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. Poperiod for reply is specified above, the maximum statutory period vire to reply within the set or extended period for reply will, by statute reply received by the Office later than three months after the mailing ed patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim vill apply and will expire SIX (6) MONTHS from , cause the application to become ABANDONE	N. sely filed the mailing date of this communication. D (35 U.S.C. § 133).	
Status				
1)⊠ 2a)⊠ 3)□	Responsive to communication(s) filed on <u>26 Jac</u> This action is <b>FINAL</b> . 2b) This Since this application is in condition for allowar closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro	•	
Dispositi	ion of Claims			
5)	Claim(s) 1,2,4-11 and 13-22 is/are pending in the drawn of the above claim(s) is/are withdrawn claim(s) is/are allowed.  Claim(s) 1,2,4-11 and 13-22 is/are rejected.  Claim(s) is/are objected to.  Claim(s) are subject to restriction and/or ion Papers  The specification is objected to by the Examine The drawing(s) filed on is/are: a) accomplicant may not request that any objection to the Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine Replacement drawing sheet(s) including the correct Theorem Replacement draw	wn from consideration.  r election requirement.  r.  epted or b) objected to by the formula drawing(s) be held in abeyance. Section is required if the drawing(s) is objected.	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).	
Priority ι	under 35 U.S.C. § 119			
12) a)	Acknowledgment is made of a claim for foreign  All b) Some * c) None of:  1. Certified copies of the priority document  2. Certified copies of the priority document  3. Copies of the certified copies of the priority document  application from the International Bureau  See the attached detailed Office action for a list	s have been received. s have been received in Applicati rity documents have been receive u (PCT Rule 17.2(a)).	on No ed in this National Stage	
2) Notic 3) Infor	t(s) se of References Cited (PTO-892) se of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) or No(s)/Mail Date	4)  Interview Summary Paper No(s)/Mail Da 5)  Notice of Informal P 6)  Other:		

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#### **DETAILED ACTION**

## Claim Rejections - 35 USC § 112

The following is a quotation of the first paragraph of 35 U.S.C. 112:

The specification shall contain a written description of the invention, and of the manner and process of making and using it, in such full, clear, concise, and exact terms as to enable any person skilled in the art to which it pertains, or with which it is most nearly connected, to make and use the same and shall set forth the best mode contemplated by the inventor of carrying out his invention.

Claim 14 is rejected under 35 U.S.C. 112, first paragraph, as failing to comply with the written description requirement. The claim(s) contains subject matter which was not described in the specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor(s), at the time the application was filed, had possession of the claimed invention.

• In claim 14, the amended portion "the second portion having at least one of a width and a length that is greater than the first portion" is not in the present specification or drawings. This is new matter.

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claim 14 is rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

• In claim 14, "a second portion within the body having a second depth that is less than the thickness of the body" is claimed. However, in fig. 3, the drawing clearly shows the second depth (d<sub>2</sub>) is equal to the thickness of the body.

## Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-2, 6-7, 11, 13, 15, and 18-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hashimoto et al. (US 6,593,159), newly cited, in view of Kawai (US 6,239,033) and CRC Handbook of chemistry and physics, 82nd Ed, by David Lide.

With regard to claims 1-2, Hashimoto et al. disclose a method of forming a semiconductor device (col. 8, line 35 et seq. and fig. 14), comprising:

- Forming a cavity 68 having a length, width and thickness in a body of a sapphire substrate 60 (col. 19, lines 52-59 and fig. 14b), the body having a thickness (col. 19, line 59), a bottom surface and a top surface (fig. 14b), the cavity opening onto at least the bottom surface (fig. 14b);
- Forming a semiconductor structure over the top surface and over the cavity 68 (fig. 14c), where at least one length and width of the cavity 68 is substantially greater than the corresponding length and width of the semiconductor structure (fig. 14c);
- Hashimoto do not disclose the substrate 60 having relatively low thermal conductivity and substantially filling the cavity 68 with at least one material

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having a greater thermal conductivity than the body. However, Kawai discloses the thermal conductivity of a sapphire body 21 is 0.4 W/cmK (Kawai col. 1, line 44) and filling the cavity 35 with Au film 37 (Kawai col. 11, lines 36-40). The CRC Handbook discloses the thermal conductivity of Au is 3.17 W/cmK (page 12-219). Thus, the thermal conductivity of filling material Au is greater than the body 21. Kawai teaches the Au filling in the cavity permits heat generated from the semiconductor structure to be radiated well to the Au film 37 and the heat of the semiconductor structure can be alleviated remarkably (Kawai col. 11, lines 36-40). Therefore, it would have been obvious to one of ordinary skill in the art to modify Hashimoto's device with the teaching of Kawai and the CRC Handbook to fill the cavity 68 with at least one material having a greater thermal conductivity than the body in order to radiate the heat from the semiconductor structure to the Au film.

With regard to claim 6, Hashimoto et al. disclose the semiconductor comprises forming a GaN semiconductor structure (col. 19, lines 13-28).

With regard to claim 7, Hashimoto et al. modified by Kawai disclose the cavity is filled with Au (Kawai col. 11, lines 36-40).

With regard to claims 11 and 15, Hashimoto et al. disclose forming the semiconductor structure occurs after forming the cavity (fig. 14b and 14c).

With regard to claim 13, Hashimoto et al. disclose the body 60 has a thickness (col. 19, line 59) and forming the cavity comprises forming the cavity 68 to a depth that is less than the

thickness of the body 60 so that the cavity opens onto the bottom surface without opening onto the top surface (fig. 14b).

With regard to claims 18-19, Hashimoto et al. disclose a p-contact 66 and is aligned with the length of the cavity (fig. 14c).

With regard to claim 20, Hashimoto et al. modified by Kawai disclose the cavity is filled to maximize thermal conductivity and structural rigidity of the semiconductor structure device (Kawai col. 11, lines 18-39 and fig. 11).

Claims 4-5 and 21-22 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hashimoto et al. (US 6,593,159) modified by Kawai (US 6,239,033) and CRC Handbook of chemistry and physics, 82nd Ed, by David Lide as applied to claim 1 above, and further in view of O'Brien et al. (US 5,059,763).

With regard to claim 4, Hashimoto et al. do not disclose laser ablating forms the cavity in the body. However, O'Brien et al. disclose forming opening 16 in a substrate 12 with laser ablation process (O'Brien col. 3, lines 27-28). O'Brien et al. teach the laser ablation improve the formation of optical quality surface in optical material (O'Brien col. 1, lines 11-15). Therefore, it would have been obvious for the one with ordinary skill in the art to modify Hashimoto's device with the teaching of Kawai and O'Brien et al. to use laser ablation process to form the cavity in the body of the substrate in order to improve the formation of optical quality surface in optical material. O'Brien et al. disclose the cavity formed in the body of the substrate with an Nd:YAG laser (O'Brien col. 3, line 39).

With regard to claim 5, Hashimoto et al. modified by Kawai and O'Brien et al. do not disclose the laser having a spot size of at least about 20 um. Since the applicant has not established the criticality of spot size stated and since these sizes are in common use in similar devices in the art, it would have been obvious to one of ordinary skill in the art to use these values in the device. Where patentability is said to be based upon particular chosen dimension or upon another variable recited in a claim, the applicant must show that the chosen dimensions are critical. In re Woodruff, 919 F2d 1575, 1578, 16 USPQ2d 1934, 1936 (Fed. Cir. 1990).

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With regard to claim 21, Hashimoto et al. modified by Kawai, CRC Handbook, and O'Brien et al. do not disclose the laser having a wavelength of about 1 um. Since the applicant has not established the criticality of the wavelength stated and since these wavelengths are in common use in similar devices in the art, it would have been obvious to one of ordinary skill in the art to use these values in the device. Where patentability is said to be based upon particular chosen dimension or upon another variable recited in a claim, the applicant must show that the chosen dimensions are critical. In re Woodruff, 919 F2d 1575, 1578, 16 USPQ2d 1934, 1936 (Fed. Cir. 1990).

With regard to claim 22, in addition to the limitations disclosed in claims 1 and 4, Hashimoto et al. modified by Kawai, CRC Handbook, and O'Brien et al. also disclose:

- The cavity comprises ablating the body with a laser (O'Brien col. 3, lines 27-28).
- The cavity forming a heat path that transports heat from the semiconductor structure away from the substrate (Kawai col. 11, lines 37-39).

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Claims 8-9 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hashimoto et al. (US 6,593,159) modified by Kawai (US 6,239,033), O'Brien et al. (US 5,059,763), and CRC Handbook of chemistry and physics as applied to claim 1 above, and further in view of Mistry et al. (US 5,731,046).

With regard to claim 8, Hashimoto et al. modified by Kawai and O'Brien et al. do not disclose filling the cavity comprises forming a seed layer on the inner surface of the cavity. However, Mistry et al. disclose forming a layer with a PECVD process via a seed crystal (Mistry col. 8, lines 5-9). Mistry et al. teach this technique would avoid any substantial physical damage to the substrate (Mistry col. 8, lines 12-13). Therefore, it would have been obvious for the one with ordinary skill in the art to modify Hashimoto's device with the teaching of Kawai and O'Brien and Mistry et al. filling the cavity comprises forming a seed layer in order to avoid physical substantial damage to the substrate.

With regard to claim 9, Hashimoto et al. modified by Kawai, O'Brien, and Mistry et al. discloses forming an additional material 37 comprises plating process (Kawai col. 11, lines 7-9).

Claims 10 is rejected under 35 U.S.C. 103(a) as being unpatentable over Hashimoto et al. (US 6,593,159) modified by Kawai (US 6,239,033) and CRC Handbook of chemistry and physics as applied to claim 1 above, and further in view of Maeda et al. (US 6,189,771).

With regard to claim 10, Hashimoto et al. modified by Kawai do not disclose filling the cavity with a metal paste. However, Maeda et al. disclose using metal paste 5 to fill a cavity 3 on the substrate (Maeda col. 4, lines 12-14). Maeda et al. teach the metal paste provides a good contact with the cavity (Maeda col. 1, lines 40-47). Therefore, it would have been obvious for the

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one with ordinary skill in the art to modify Hashimoto's device with the teaching of Kawai, CRC Handbook, and Maeda et al. to provide a metal paste filling the cavity in order to make a good contact.

Claims 14 and 16-17 (in so far as they are understood) are rejected under 35 U.S.C. 103(a) as being unpatentable over Hashimoto et al. (US 6,593,159) modified by Kawai (US 6,239,033) and CRC Handbook of chemistry and physics as applied to claim 1 above, and further in view of Zhou (US 5,449,930), newly cited.

With regard to claim 16, in addition to the limitations disclosed in claim 1 above, Hashimoto et al. also disclose:

Hashimoto et al. do not disclose the cavity has a depth that is equal to the thickness of the body. However, Zhou discloses a cavity has a depth that is equal to the thickness of the body 115 (Zhou col. 11, line 48 et seq. and fig. 15). Zhou teaches the cavity can best located underneath the semiconductor structure (Zhou col. 12, lines 21-22) with the heat conductor metal 133 filling the cavity (fig. 15) and thereby improving the heat dissipation (Zhou col. 4, lines 43-47). Therefore, it would have been obvious at the time the invention was made to modify Hashimoto's device with the teaching of Kawai, CRC Handbook, and Zhou to have a through cavity in the body in order to improve the heat dispersion of the semiconductor structure.

With regard to claims 14 and 17, in addition to the limitations disclosed in claims 1, 15 and 16 above, Hashimoto et al. modified by Kawai, CRC Handbook, and Zhou disclose the

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cavity comprises a first portion having a first depth that is less than the thickness of the body (under island 85 in Zhou fig. 10) and a second portion within the body having a second depth that is equal to the thickness of the body (Zhou fig. 10), so that the cavity opens onto the bottom surface and the top surface (Zhou fig. 10), the second portion having at least one of a width and a length that is greater than the first portion (Zhou fig. 10 to 12).

## Response to Arguments

Applicant's arguments with respect to claims1-2 and 14-17 have been considered but are moot in view of the new ground(s) of rejection.

#### Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event,

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however, will the statutory period for reply expire later than SIX MONTHS from the date of this

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final action.

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Wai-Sing Louie whose telephone number is (571) 272-1709. The

examiner can normally be reached on 7:30 AM to 4:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the

organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent

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Patent Examiner

Wsl

April 5, 2006.